Superconducting quantum interference device with frequency-dependent damping: Readout of flux qubits

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(Received 7 February 2005; published 11 July 2005)

Recent experiments on superconducting flux qubits, consisting of a superconducting loop interrupted by Josephson junctions, have demonstrated quantum coherence between two different quantum states. The state of the qubit is measured with a superconducting quantum interference device (SQUID). Such measurements require the SQUID to have high resolution while exerting minimal backaction on the qubit. By designing shunts across the SQUID junctions appropriately, one can improve the measurement resolution without increasing the backaction significantly. Using a path-integral approach to analyze the Caldeira-Leggett model, we calculate the narrowing of the distribution of the switching events from the zero-voltage state of the SQUID for arbitrary shunt admittances, focusing on shunts consisting of a capacitance \( C_s \) and resistance \( R_s \) in series. To test this model, we fabricated a dc SQUID in which each junction is shunted with a thin-film interdigitated capacitor in series with a resistor, and measured the switching distribution as a function of temperature and applied magnetic flux. After accounting for the damping due to the SQUID leads, we found good agreement between the measured escape rates and the predictions of our model. We analyze the backaction of a shunted symmetric SQUID on a flux qubit. For the given parameters of our SQUID and realistic parameters for a flux qubit, at the degeneracy point we find a relaxation time of 113 \( \mu \)s, which limits the decoherence time to 226 \( \mu \)s. Based on our analysis of the escape process, we determine that a SQUID with purely capacitive shunts should have narrow switching distributions and no dissipation.

DOI: 10.1103/PhysRevB.72.024513

PACS number(s): 03.67.Lx, 85.25.Cp, 85.25.Dq

I. INTRODUCTION

Superconducting devices are attractive candidates for quantum bits (qubits) because of their manufacturability, controllability, and scalability. As with any qubit, strong interaction is necessary to control its state and to measure the outcome of a computation; however, the quantum properties are very fragile and only become manifest in almost total isolation. Reconciling these contradictory requirements is the fundamental challenge in building a quantum computer.

Quantum coherent behavior has been demonstrated in devices based on the flux in a superconducting ring interrupted by Josephson junctions. With an applied flux bias of \( \Phi_0/2 \), where \( \Phi_0 = h/2e \) is the flux quantum, the qubit has two degenerate states corresponding to its screening flux being oriented parallel or antiparallel to the applied flux. The detector used to measure the qubit must have sufficient sensitivity to distinguish between the two states of the qubit efficiently, but must not cause excessive decoherence during the quantum evolution of the system. A conventional, resistively shunted dc superconducting quantum interference device (SQUID) is an excellent linear flux detector with high sensitivity when operated in a flux-locked loop, but noise currents generated by the shunt resistors induce qubit decoherence, rendering it unsuitable.

Because the qubit is only a two-state system, a linear detector provides more information than necessary. An unshunted SQUID is widely used as a flux comparator to distinguish the two states of the qubit, and furthermore has negligible dissipation in the superconducting state, making it an attractive candidate for a qubit meter. For a given bias current, one value of flux causes the SQUID to switch, generating an easily detectable voltage, while for another flux the SQUID remains in the supercurrent state. By properly engineering the appropriate parameters, one can use this device to discriminate between the two states of the qubit.

While the unshunted SQUID has minimal inherent dissipation, the leads coupling it to external measurement electronics can drive noise currents around the loop, causing decoherence in the qubit, particularly if the SQUID has typical fabrication asymmetries. This decoherence can be mitigated by reducing the mutual inductance between the SQUID and the qubit; however, the concomitant reduction in the qubit signal coupled to the SQUID makes it important to optimize its resolution.

The switching of the SQUID out of the zero-voltage state is not necessarily sharp. Switching occurs when the phase particle representing the state of the SQUID escapes from the effective tilted washboard potential; the distribution of switching probabilities is governed by thermal activation over and quantum tunneling through a barrier. At high temperatures, the thermal escape rate dominates and the distribution narrows as the temperature is lowered; however, below a crossover temperature \( T^* \), the quantum rate dominates and the distribution width is constant with decreasing temperature, limiting the resolution of unshunted SQUIDs at low temperature. The crossover temperature \( T^* \) is determined by the plasma frequency of the SQUID. Appropriately engineered shunts in parallel with the SQUID junctions can renormalize the plasma frequency, depressing the crossover
temperature, and leading to narrower switching distribution widths and improved SQUID resolution at low temperatures. Indeed, in an early experiment that provided spectroscopic evidence for quantum coherence in a flux qubit the authors placed a discrete capacitor across their SQUID.

In this paper we consider the escape from the supercurrent state of a dc SQUID with arbitrary shunts across the junctions, with emphasis on a shunt that consists of a resistor \( R_s \) in series with a capacitor \( C_s \). In Sec. II, we calculate the switching current distribution widths for such a device, and in Sec. III fit this model to the measured escape width as a function of temperature for an experimental device. In Sec. IV, we treat the problem of decoherence of a flux qubit coupled to an arbitrarily shunted SQUID using the spin-boson model. Using the parameters for the experimental RC-shunted SQUID as a case study, we describe a set of qubit parameters which lead to very low relaxation and dephasing rates for the qubit due to the RC shunts, while allowing single-shot resolution of the qubit state. In Sec. V we conclude that a SQUID with purely capacitive shunts provides the ideal combination of narrow switching distributions without contributing additional decoherence.

II. CALCULATIONS OF ESCAPE RATES

We consider a flux qubit coupled to a dc SQUID with a mutual inductance \( M_{QS} \), shown in Fig. 1. The SQUID consists of a superconducting loop of inductance \( L_s \) containing two Josephson junctions, each with thermodynamic critical current \( I_0 \), capacitance \( C_j \), and shunt admittance \( Y \). The dynamics of the SQUID are described by the phase differences across the junctions \( \gamma_{1,2} \). Leads attached to the SQUID loop can be used to drive a bias current \( I_b \), through the SQUID and to measure the voltage across it. The SQUID is biased with an externally applied flux \( \Phi_S = \Phi_0 \Phi_0 / 2\pi \), and the qubit couples an additional flux \( \Delta \Phi_Q = \pm M_{QS} \Delta \Phi_Q \) depending on the sense of its circulating current \( I_0 \). A variation in the total flux coupled to the SQUID changes the circulating current \( I_s \) flowing around the SQUID loop and the value of \( I_b \) at which the SQUID has a probability \( p \) of switching out of the zero-voltage state, \( I_s^{(p)} \). This flux response \( I_s^{(p)}(\Phi_0) / 2I_0 \) is governed by the screening parameter \( \beta_s = 2L_s I_0 / \Phi_0 \). A square pulse of bias current, with height \( I_b \) and duration \( t_b \), causes the SQUID to switch with a probability depending on these parameters, the qubit state and temperature. Our goal is to design a SQUID and shunts so that we can distinguish the two states of the qubit in a single shot, with well characterized and small backaction from the SQUID to the qubit. Single shot implies that when the qubit is in one state, a particular value of \( I_b \) causes the SQUID to switch with a small probability, while when the qubit is in the other state, the same \( I_b \) causes the SQUID to switch with a probability approaching unity.

A useful metric for characterizing the sensitivity of a particular SQUID readout scheme is the resolution \( \rho \) which we can express in terms of the switching distribution width \( \Delta \) and the slope of the flux modulation curve \( dI_s^{50\%} / d\Phi_S \) through the equation

\[
\rho(\Delta p) = \frac{\Delta}{dI_s^{50\%} / d\Phi_S}.
\]

Here, \( \Delta p \) is a parameter that indicates how much of the switching distribution is to be included (Fig. 2). Thus, the criterion for single-shot readout with a confidence level of \( \Delta p \) is \( \rho(\Delta p) \leq 2\Delta \Phi_Q \).

Equation (1) shows that the resolution of a readout SQUID can be improved either by increasing \( |dI_s^{50\%} / d\Phi_S| \) or by narrowing \( \Delta I_s^{(p)} \). The flux modulation characteristics, which are determined by the critical current and loop inductance, are often constrained by considerations related to the qubit. In particular, designing a readout SQUID which can also function as a controllable qubit coupler leads to the regime \( \beta_s \leq 1 \). In this paper we focus on optimizing \( \rho \) by minimizing \( \Delta I_s^{(p)} \).

The switching distribution width of the readout SQUID is determined by two stochastic processes, thermal activation and quantum tunneling. Switching from the supercurrent to the voltage state occurs when the phase particle, representing the state of the SQUID, escapes from a metastable local minimum of the potential energy to a running state. In the thermal regime, the rate at which the SQUID switches is given by the Arrhenius expression

\[
\Gamma(T) = (\omega_c / 2\pi) \exp(-U_0/k_B T),
\]

where \( \omega_c \) is the frequency of small oscillation aligned with the direction of escape, renormalized by coupling to environmental degrees of freedom, and \( U_0 \) is the height of the barrier blocking escape.

FIG. 1. Schematic of flux qubit coupled to readout SQUID.

FIG. 2. Idealized SQUID switching distribution. As \( I_b \) is increased, the probability of the SQUID switching increases from 0 to 1 over a characteristic width \( \delta I_s^{50\%} \).

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An intuitive model of this escape process is provided by the one-dimensional dynamics of a single, undamped Josephson junction with critical current $I_0$ and capacitance $\hat{C}_j$. In this case, for $I_b \sim I_0$, we can write closed form approximations for the barrier height $\hat{U}_0$ and the frequency of small oscillations $\dot{\omega}_0$ as\(^\text{13}\)

$$\hat{U}_0 = \frac{4(\sqrt{2}I_0/\Phi_0/s)}{(1-I_b/I_0)^{3/2}} \quad (3)$$

and

$$\dot{\omega}_0 = \sqrt{\frac{2}{\pi I_0/\Phi_0 \hat{C}_j (1-I_0^2/I_0^2)^{1/4}}}. \quad (4)$$

We rewrite Eqs. (2) and (3) in the scaling form

$$\hat{\Gamma}_{th}(T) = \frac{\dot{\omega}_0}{2\pi} \exp \left[-\left(1 - \frac{I_b}{I_0}\right) \left(\frac{\hat{U}_0}{k_BT}\right)^{3/2}\right], \quad (5)$$

to see that the distribution width in $I_b$ scales as $T^{2/3}$.

In the thermal regime, the switching distributions narrow with decreasing temperature so that if the readout SQUID remained in this regime one could resolve arbitrarily small fluxes by cooling to sufficiently low temperatures. However, as the thermal fluctuations diminish, they leave behind quantum fluctuations which cause the junction to switch through tunneling and saturate the switching width to a limiting value at low temperatures. Below $T^*$, the switching rate saturates towards the constant value

$$\Gamma_q = \hat{\Gamma}_{th}(T^*) = (\omega_0/2\pi)\exp(-U_0/k_BT^{*}), \quad T < T^*. \quad (6)$$

Thus, the problem of making a sensitive readout SQUID can be recast as one of suppressing the crossover temperature, given by\(^\text{12}\)

$$T^* = h\omega_0/2\pi k_B. \quad (7)$$

For a SQUID with given $\beta_L$, $\rho$ is determined at low temperatures by $T^*$, and hence by $\omega_0$. As we shall see, $\omega_0$ can be engineered with a properly designed shunt. Previous experiments have measured the crossover temperature for unshunted dc SQUIDs\(^\text{14,15}\).

We now calculate the crossover temperature for a SQUID with arbitrary loop inductance, critical current, shunt admittance, flux bias, and current bias. We use the appropriate nonohmic Caldeira-Leggett model, which contains terms renormalizing the capacitance as well as dissipative terms, and solve for the escape rates using the path-integral representation of the imaginary part of the free energy. We apply this formalism to a single, shunted Josephson junction to find an analytical formula for $T^*$ that depends on the shunt, the plasma frequency, and the barrier height. We numerically extract these parameters from the full SQUID potential, which we shall see gives good agreement with experimental data. Thus, we reduce the SQUID with each junction shunted by an admittance $Y$ to a single junction shunted by an effective admittance $\hat{Y} = 2Y$ (Fig. 3). The equivalent junction has a capacitance $\hat{C}_j = 2C_p$, a critical current $\hat{I}_0$ which depends on $\Phi_3$ with a maximum value $2I_0$, and a bare plasma frequency $\dot{\omega}_0$ that is derived from the SQUID plasma frequency $\omega_0(\Phi_3, I_b, \beta_L)$. This approximation neglects the SQUID loop inductance $L_S$, but is valid because the Josephson inductance of the junctions diverges near the escape point.

To compute the escape rates from Eqs. (2) and (6) for a SQUID with arbitrary $\beta_L$ and $\Phi_S$, we need to consider the full two-dimensional potential energy surface for the dc SQUID. We replace the single junction quantities $\hat{U}_0$ and $\dot{\omega}_0$ with those calculated from the full SQUID potential, $U_0$ and $\omega_0$, which we use to treat the escape process in one dimension along a cut through the full SQUID potential.

The junction potential energy $\hat{U}$ is replaced with the SQUID potential energy $U = U_J + U_I$, where

$$U_J = (L_d/2)[(I_b/2) - J_S]^2 + [(I_b/2) + J_S]^2] \quad (8)$$

is the inductive energy, and

$$U_I = -\frac{\Phi_0}{2\pi} \left[ I_b(\cos \gamma_1 + \cos \gamma_2) + I_b^2 \frac{\gamma_1 + \gamma_2}{2} \right] \quad (9)$$

is the Josephson energy. Here, $J_S$ and $\gamma_1, \gamma_2$ are connected through the fluxoid condition

$$\gamma_1 - \gamma_2 = 2\pi L_d I_b/\Phi_0 + \phi_S. \quad (10)$$

The observable static solutions of this potential correspond to metastable minima along the valley of minimum $U_I$ at points $x_i$. The junction switches to the voltage state when the state of the system moves from $x_0$ to $x_1$ through a barrier of height $U_0$ at the saddle point $x_{01}$ between the two minima. From this we see that $U_{01} = U(x_{01}) - U(x_0)$, and that $\omega_0$ is related to the curvature of $U$ at $x_0$.

To find $x_0$ and $x_{01}$ we use previously derived analytical approximations\(^\text{10}\) as starting points for exact numerical solutions. First, we find the critical point $x_c$ where the saddle point disappears by solving the system of three equations

$$\frac{\partial U}{\partial \gamma_1} = \frac{\partial U}{\partial \gamma_2} = \frac{\partial U}{\partial \phi_s} = \left(\frac{\partial^2 U}{\partial \gamma_1 \partial \gamma_2}\right)^2 = 0 \quad (11)$$

in three unknown parameters $\gamma_1$, $\gamma_2$, and $\phi_s$. We then use the third-order expressions given in Eqs. (12) and (13) of Ref. 10 to find starting points sufficiently close to the location of the true minimum and saddle point, so that numerical methods converge. This allows us to find $U_0$ and $\omega_0$ with an efficient, automated procedure. The results are displayed graphically in Fig. 4.

We derive the effective Lagrangian\(^\text{16}\) using a method pioneered by Leggett based upon the classical equation of motion. Current conservation for the single junction can be ex-
pressed in terms of the inverse Fourier transform $\mathcal{F}^{-1}$ of the effective shunt admittance $Y(\omega)$ as

$$I_b = I_0 \sin \gamma + \mathcal{F}^{-1} \{ (\Phi_0/2\pi) i\omega [\hat{Y}(\omega) + 2i\omega C_j] \},$$  \hspace{1cm} (12)

where $\gamma$ is the phase difference across the junction. The Fourier transform of this equation yields

$$K(\omega)\gamma = -\mathcal{F}(\partial U/\partial \gamma),$$  \hspace{1cm} (13)

where $\hat{U} = (\Phi_0/2\pi) (I_b \gamma - I_0 \cos \gamma)$ is the single junction potential and

$$K(\omega) = (\Phi_0/2\pi) i\omega [\hat{Y}(\omega) + 2i\omega C_j]$$  \hspace{1cm} (14)

is the frequency-dependent linear dynamical operator.\textsuperscript{16}

To determine the tunneling rate using the free energy method, we need to find the effective action of the system in imaginary time $\tau$. At finite temperature, the partition function is a path integral over all periodic paths $g(\tau)$ with $q(ih/k_BT) = q(0)$. We Fourier expand these paths as $q(\tau) = \sum q(\omega_n) \exp(-i\omega_n \tau)$, where $\omega_n = 2\pi nk_BT/h$ are the Bose-Matsubara frequencies, to find the effective action

$$S_{\text{eff}}[q(\omega)] = (1/2\pi) \sum_n K(-i|\omega_n|)|q(\omega_n)|^2 + S_U.$$  \hspace{1cm} (15)

Here, $S_U$ is the contribution of the potential energy and the analytically continued dynamical operator is given by $\tilde{K}(\omega) = K(-i|\omega|)$.

If the barrier is not too low, it is sufficient to evaluate the contributions to the partition function around the classical solutions: the periodic paths which make $S_{\text{eff}}$ stationary. The escape can be driven by thermal or quantum fluctuations. These mechanisms can be distinguished by two classes of stationary solutions: thermal escape corresponds to constant paths, $q(\omega) = 0$ for $\omega \neq 0$; quantum tunneling corresponds to nontrivial periodic paths (instantons). The highest temperature with an instanton solution is $T^\ast$.

The instanton appears as a small-amplitude oscillation around the minimum of the inverted potential described by

$$\tilde{K}(\omega) - 2C_j\dot{\omega}_0^2 = 0.$$  \hspace{1cm} (16)

This equation for $\omega$, yields $T^\ast$ through Eq. (7).

### III. EXPERIMENTAL RESULTS

To design a SQUID to measure a flux qubit, one wants to minimize $\rho$ while exerting a weak backaction on the qubit due to the shunts. One choice for a shunt which satisfies this compromise is an admittance $Y$ (Fig. 1) which consists of a capacitor $C_s$ in series with a resistor $R_s$. The relevant frequency for the SQUID damping is the plasma frequency $\omega_0$ of the equivalent single junction.\textsuperscript{17} We design the SQUID and qubit so that $\omega_0/2\pi$ is more than an order of magnitude greater than the qubit level splitting frequency $\nu$. We choose $R_s$ and $C_s$ such that $1/2\pi R_s C_s$ is larger than $\nu$. At $\omega_0/2\pi$, the capacitor has a negligible reactance and the resistor damps the SQUID; in contrast, at $\nu$ the shunt capacitor has an impedance greater than that of free space.

We fabricated an RC-shunted SQUID with Al-AlO$_x$-Al tunnel junctions on an oxidized Si substrate using electron-beam lithography and double-angle evaporation (Fig. 5). The junction areas were $350 \times 260$ nm$^2$, corresponding to a capacitance $C_j = 9.3$ fF determined from separate measurements on similar junctions. The shunt capacitors were deposited in the same Al-AlO$_x$-Al layer as the tunnel junctions in an interdigitated style, with 0.6 $\mu$m wide fingers spaced by 0.8 $\mu$m. We estimate each capacitor to have a value $C_j = 20$ fF, using the simple design rule that when the gap is equal to the width, and larger than the oxide thickness, the capacitance of interdigitated capacitors fabricated on silicon wafers is $C (\text{ff}) \approx 0.1 \times N \times L$ $(\mu$m), where $N$ is the number of fingers in each electrode, and $L$ is the length of each finger.\textsuperscript{18,19} The shunt resistors were patterned in a 42 nm thick AuCu film to yield $R_s = 40$ $\Omega$, based on the measured resistor area and separate measurements of the sheet resistance. The device was cooled in a dilution refrigerator with all electrical leads to the sample heavily filtered at several different temperatures with a combination of lumped circuit and copper powder low-pass filters.\textsuperscript{13} The sample was enclosed in a Pb-plated cavity to eliminate external magnetic field fluctuations.

Measurements of $I_{s\text{res}}^{50\%}$ were made by adjusting the amplitude of a 4 $\mu$s long trapezoidal bias current pulse until the voltage state was detected 50% of the time out of 5000 averages. The flux applied to the SQUID was varied to produce the modulation curve shown in Fig. 6(a). By fitting the shape of the flux modulation curve to calculations based on the SQUID potential we estimated $\beta_L = 0.95$; with the computed value $L_3 = 500$ pH we find $I_0 = 1.96$ $\mu$A. The rise in $I_{s\text{res}}^{50\%}$ near $\Phi_0/2$ is due to the switching from the $L_3 C_j$-resonance of the SQUID, which produces a step in the current-voltage characteristic of the SQUID. This step modulates with flux with period $\Phi_0/2$ out of phase with the modulation of $I_{s\text{res}}^{50\%}$.\textsuperscript{20}
SUPERCONDUCTING QUANTUM INTERFERENCE DEVICE

By successively measuring the switching probability as a function of the amplitude of the applied bias current pulse we acquired the curve shown schematically in Fig. 2 to determine $\delta f(90\%)$ versus $\Phi_S$ [Fig. 6(b)]. From these measurements, we compute the resolution $\rho(90\%)$ as a function of $\Phi_S$. The results [Fig. 6(c)] show that the resolution is roughly constant at 15$m\Phi_0$ for $\Delta p=90\%$ and 28$m\Phi_0$ for $\Delta p=99\%$ over a range $0.2\Phi_0 < |\Phi_S| < 0.4\Phi_0$, with the resolution degenerating near $\Phi_S=n\Phi_0/2$ ($n$ is an integer).

We measured $\delta f(90\%)$ for several values of $\Phi_S$ at temperatures between 24 and 500 mK, as shown in Fig. 7. The width remains constant below $T \sim 200$ mK, indicating the quantum tunneling regime, and increases as a power law in the thermal regime. The fractional width increases as the flux bias moves away from $n\Phi_0$.

To determine the effect of the RC-shunt, we compare these data to the model described in Sec. II. A nuance in this calculation is that, because $T^*$ depends on the plasma frequency, which in turn is a function of the bias current, one must solve self-consistently for the escape point at $T^*$.

For a SQUID with each junction shunted by $R_s$ and $C_s$ in series, the effective shunt admittance across the equivalent single Josephson junction (Fig. 3) is

$$\hat{Y}(\omega) = 2\omega C_s \omega_0 / (\omega - i \omega_r),$$  
(17)

where $\omega_r = 1/R_sC_s$. Using Eq. (13) and applying the linear response formalism as described by Leggett$^{16}$ we find that $\omega_r$ is the real root of the cubic equation

$$\omega_r^3 + \omega_r(1 + \kappa)\omega_r^2 - \omega_0^2\omega_r - \omega_r\omega_0^2 = 0,$$  
(18)

where $\kappa = C_s/C_J$. This root can be found in closed form using Cardano’s formula.$^{21}$ The parametric dependence of $T^*$ is shown in Fig. 8. We can identify a number of limits:

1. Very small rolloff frequency, $\omega_r \rightarrow 0$: $\omega_r = \omega_0$. This recovers the result for an unshunted junction.

2. Small rolloff frequency, $\omega_r \rightarrow 0$, $\kappa\omega_r$ arbitrary (corresponds to the rolloff frequency with the junction capacitance of appreciable size): $\omega_r = \kappa\omega_0/[1 + (2\omega_0/\kappa\omega_r)^2]^{1/2} - 1]/2$. This describes a light particle with damping.

3. High rolloff frequency, $\omega_r \gg \omega_0$: $\omega_r = \omega_0/(\kappa + 1)^{1/2}$.

The capacitor renormalizes the plasma frequency of the junction.

For a set of RC-shunted SQUIDs with fixed $C_s$ and variable $R_s$, the first limit corresponds to $R_s \rightarrow \infty$, so that the shunt has no effect on the system. As $R_s$ is decreased, the enhanced damping suppresses $T^*$. As $R_s$ is further decreased, the dominant effect is that the shunt capacitance renormalizes the plasma frequency, suppressing $T^*$ by a factor asymptotically.
approaching \((1 + \kappa)^{-1/2}\). Thus, one can reduce \(T^*\) by either decreasing \(R_s\), increasing \(C_s\), or both.

Using the parameters for our RC-shunted SQUID, we obtain escape widths that are much larger than our measured values. By treating the shunt capacitance \(C_s\) as a free parameter while keeping the rest of the device parameters unchanged, we find good agreement between theory and experiment with \(C_s=153\) fF, which yields \(T^*=171\) mK at \(\Phi_s=0.01\Phi_0\). However, this value of \(C_s\), which we shall refer to as case A, is a factor of 8 greater than the estimated value of 20 fF. In fact, we believe that a major contribution to the escape width for one such device to obtain an effective width for corresponding unshunted SQUID with \(R_s=\infty\) at \(\Phi_s=0.01\Phi_0\).

To quantify the effect of RC-shunts on a SQUID when \(R_s\) is included, we note that a calculation for a SQUID with identical parameters, including \(R_s\) but with no RC-shunts, yields \(T^*=222\) mK for \(\Phi_s=0.01\Phi_0\) and a saturated 90% switching width of \(\delta_0^{0.9}/I_s^{0.9}=0.0149\).

The damping effects of the SQUID bias leads us to include off-chip series resistors in subsequent designs. We fabricated similar SQUIDs using 250 \(\Omega\) on-chip resistors in series with the bias lines and with no RC-shunts. Using the theory developed in this paper, we fitted the low-temperature switching widths for one such device to obtain an effective lead impedance \(R_f=234\) \(\Omega\), which can be compared to the expected value of 300 \(\Omega\) when the 50 \(\Omega\) line impedance is included. Through separate experiments, we verified that the power dissipated in this series resistance during the bias current pulses does not lead to appreciable heating.

IV. CALCULATIONS OF DECOHERENCE DUE TO RC-SHUNTS

In order for the enhanced sensitivity of the RC-shunted SQUID to be useful for measuring a flux qubit, it is important that the shunts not couple excessive dissipation to the qubit and thus limit decoherence times. In this section, we calculate the decoherence due to a SQUID with arbitrary shunt admittances (Fig. 1). The calculations are performed for a single-junction qubit for definiteness, but the results hold for any flux qubit, including three-junction qubits. In contrast to previous calculations, we include the self-inductance of the SQUID loop, and the junctions are shunted individually.

In the spin-boson model, decoherence times are obtained from the environmental spectral density function \(J(\omega)\), which can be found from the classical friction the phase of the qubit experiences from its environment. For a total qubit flux \(\Phi_Q\) and qubit potential \(U_Q(\Phi_Q)\), one finds \(J(\omega)=[(L_QJ_Q)^2/2\pi\hbar]\sigma[D(\omega)]\), where \(D(\omega)\) is the linear coefficient in the Fourier-transformed equation of motion

\[
D(\omega)\Phi_Q^* = -\partial U_Q/\partial \Phi_Q, \tag{20}
\]

with the environmental coordinates eliminated.

We now model the decoherence induced when the SQUID is in its “off” state, that is, for zero bias current, using this formalism. To do this we must find the classical equation of motion for the qubit, including influences from the SQUID. We begin by splitting the total fluxes through the SQUID and the qubit into external and screening fluxes, \(\Phi^e_Q=\Phi_Q+\Phi^s_Q\), and \(\Phi^e_s=\Phi_s+\Phi^s_s\), respectively, where \(\Phi_Q\) and \(\Phi_s\) are fluxes from external sources. The screening fluxes arise from circulating currents in the SQUID \(J_S\) and qubit \(J_Q\), as

\[
\begin{pmatrix}
\Phi_Q^e \\
\Phi_s^e
\end{pmatrix} = 
\begin{pmatrix}
L_Q & M_{QS} \\
M_{QS} & L_s
\end{pmatrix} 
\begin{pmatrix}
J_Q \\
J_S
\end{pmatrix}, \tag{21}
\]

where \(L_Q\) is the inductance of the qubit which has mutual inductance \(M_{QS}\) to the SQUID with self-inductance \(L_s\).

Equation (21) allows us to express the fluxes through currents by matrix inversion,

\[
\begin{pmatrix}
J_Q \\
J_S
\end{pmatrix} = 
\frac{1}{M_s^2} \begin{pmatrix}
L_s & -M_{QS} \\
-M_{QS} & L_Q
\end{pmatrix} 
\begin{pmatrix}
\Phi_Q^e \\
\Phi_s^e
\end{pmatrix}, \tag{22}
\]

where \(M_s^2=L_QL_s-M_{QS}^2=0\).
We can write current conservation at a node in the SQUID loop as \( I_c = I_v + I_y + I_f \), where the terms on the right are the current through the junction capacitance, junction inductance, and shunt admittance, respectively. Proceeding term by term, we have

\[
I_c = C_f \dot{V}_v = (C_f \Phi_0 / 2\pi) \overline{\gamma}_1,
\]

where we have introduced the junction voltages \( V_j \) and used dots to denote time derivatives. For \( I_y = 0 \), the symmetry of the two junctions is unbroken, so that Eq. (10) implies

\[
\overline{\gamma}_1 = - \overline{\gamma}_2 = (\pi \Phi_0) (\Phi_s^2 + \Phi_y^2) \cdot (26)
\]

Thus, we have \( I_c = (C_f / 2) \Phi_s^2 \). The next term is given simply by the Josephson current-phase relation, \( I_j = I_0 \sin \gamma_j \). Finally, the current through the shunt is simply \( I_y = V_j \). Thus, the equation of motion for the SQUID can be written as

\[
(C_f / 2) \Phi_s^2 + I_0 \sin [\pi (\Phi_s + \Phi_y) / \Phi_0] + (Y / 2) \Phi_s^2 = (L_0 \Phi_s - M_{Q3} \Phi_y) / M_s^2.
\]

We expand the sine term for small \( \Phi_s^2 / \Phi_0 \) and Fourier transform to obtain

\[
\left[ - \omega^2 C_s / 2 + i \omega Y / 2 + L_0 / M_s^2 \right] \Phi_s^2 \cos (\pi \Phi_s / \Phi_0) = - I_0 \sin (\pi \Phi_s / \Phi_0) - (M_{Q3} / M_s^2) \Phi_y^2.
\]

We henceforth simplify the notation by introducing the effective inductance of the SQUID \( L_{eff} \), where \( 1 / L_{eff} = L_0 / M_s^2 + (I_0 / \Phi_0) \cos (\pi \Phi_s / \Phi_0) \).

We perform a similar analysis for the qubit, in which current conservation yields

\[
C_0 \Phi_s^2 + J_0 \sin [2 \pi (\Phi_0 + \Phi_s^2) / \Phi_0] = (L_s \Phi_s^2 - M_{Q3} \Phi_y) / M_s^2.
\]

We do not linearize the Josephson term here, but instead include it in \( L_0 \) in Eq. (20). We now Fourier transform, regroup terms, and substitute \( \Phi_s \) from Eq. (26) into Eq. (27) to find the Fourier-transformed equation of motion for the qubit in the form prescribed by Eq. (20), giving

\[
D(\omega) = (L_0 / M_s^2) - \omega^2 C_s + (M_{Q3}^2 / M_s^2)
\]

\[
\times (\omega^2 C_s - i \omega Y / 2 + 1 / L_{eff})^{-1}.
\]

Using \( M_s^2 = L_0 L_s \), we can write

\[
J(\omega) = (J_0^2 / M_s^2 / 2 \pi h L_0) \text{Im} \left[ (\omega^2 C_s - i \omega Y / 2 + 1 / L_{eff})^{-1} \right].
\]

This is the central result of this section.

We now consider the specific case of a purely resistive shunt, \( Y = 1 / R_s \), for which Eq. (29) becomes

\[
J(\omega) = \frac{a}{4} \left[ \left( 1 - \omega^2 C_s / L_{eff} \right)^{-1} + \omega^2 L_{eff} / R_s^2 \right].
\]

This expression is ohmic at low frequencies with \( a = \lim_{\omega \to 0} 4 J(\omega) / \omega = J_0^2 M_s^2 / 2 \pi h L_0 \). The internal effective LC-resonance of the SQUID appears as a high-frequency peak in \( J(\omega) \), which may be broadened by the damping.

For the case of the RC-shunt, we substitute \( Y(\omega) = \omega_0 C_s / (\omega - i \omega_0) \) into Eq. (29) to find

\[
J(\omega) = (\omega / 2 \pi)^3 \left[ (4 \omega^2 L_{eff} C_{eff} - 1)^2 + (\omega / \omega_0)^2 (\omega^2 C_{eff} L_{eff} - 2)^2 \right]^{-1},
\]

with effective capacitance \( C_{eff} = C_s / 2 + C_s / 2 \). Since \( J(\omega) \) scales as \( \omega^3 \), it is superohmic at low frequencies; at higher frequencies it contains a modified version of the LC-resonance peak of the SQUID. This expression is valid for a symmetric SQUID with zero current bias, where to first order the internal circulating current mode is decoupled from external impedance sources.8 To account for the effect of \( R_s \) away from this special point, one must numerically solve the equations governing the coupling of the SQUID circulating current to external decoherence.26

To estimate the contribution of an RC-shunted SQUID to decoherence, we consider a symmetric SQUID with the escape widths of our measured device coupled to a hypothetical flux qubit with \( M_{Q3} \) chosen to yield single-shot resolution at the 99% level: \( L_c = 500 \) pF, \( I_0 = 1.96 \) mA, \( C_s = 9.3 \) fF, \( R_s = 40 \) \Omega, \( L_0 = 200 \) pF, \( M_{Q3} = 96 \) pH, and \( J_0 = 0.3 \) mA. We will consider both case A, with \( C_s = 153 \) fF and \( R_s = \infty \), and case B, with \( C_s = 20 \) fF and \( R_s = 52 \) \Omega, as described in Sec. III both at a flux bias of \( \Phi_s = \Phi_0 / 4 \), where the SQUID resolution is near optimal [Fig. 6(c)], and with \( I_y = 0 \) so that Eq. (31) is valid. These parameters correspond to plasma frequencies in the SQUID junctions of 80 and 120 GHz and roll-off frequencies \( \omega_s / 2 \pi = 26 \) and 200 GHz, for cases A and B, respectively. We assume arbitrarily that the qubit has a tunneling frequency \( \Delta / h = 1 \) GHz. The behavior of \( J(\omega) \) calculated from Eq. (31) is shown in Fig. 9. We see that \( J(\omega) \) exhibits the LC-resonance of the SQUID near 51 GHz for case A and
FIG. 10. Dephasing ($\tau_\phi$, black) and relaxation ($\tau_R$, gray) times for flux qubit coupled to RC-shunted SQUID. Solid lines correspond to case A and dashed lines correspond to case B.

89 GHz for case B, while at the frequencies near 1 GHz relevant to the qubit it is well within the $\omega^3$ regime for both cases.

Finally, we use $J(\omega)$ to calculate relaxation ($\tau_R^i$) and dephasing ($\tau_\phi^i$) rates for our qubit due to the RC-shunts:

$$\tau_R^i = 4\pi(\Delta/\nu)^2J(2\pi\nu)\coth(h\nu/2k_BT)$$

and

$$\tau_\phi^i = \tau_R^i/2 + 2\pi\alpha(\epsilon/\nu)^2(k_BT/h).$$

Here, $\nu=(\Delta^2+\epsilon^2)^{1/2}$ is the qubit frequency, where $\epsilon$ is the bias of the qubit relative to the degeneracy point. For the RC-shunted SQUID, $\alpha$ vanishes because of the $\omega^3$ dependence at low frequencies, so that $\tau_\phi = 2\tau_R$. In Fig. 10 we plot $\tau_R$ and $\tau_\phi$ versus $\epsilon$. At $\epsilon=0$, $\tau_R=1.9$ $\mu$s and $\tau_\phi=3.9$ $\mu$s for case A, while for case B $\tau_R=113$ $\mu$s and $\tau_\phi=226$ $\mu$s; both times decrease with increasing $\epsilon$ for both cases because of the $\omega^3$ dependence of $\alpha$. For low $\epsilon$, $\tau_\phi$ is much longer than values currently observed in flux qubits without echoes, so that the readout device does not contribute significantly to dephasing. Hence, the RC-shunted SQUID achieves single-shot readout while inducing negligible decoherence in the qubit. By contrast, a readout SQUID with the same parameters except for purely resistive shunts of $R_s=40$ $\Omega$ would cause dephasing in 5.7 ns.

In this analysis we have assumed complete symmetry of the SQUID. We note that for a symmetric SQUID with zero bias current, noise currents generated by $R_s$ decouple from the qubit to linear order, however, even small asymmetries can cause the qubit to couple strongly to $R_s$, rapidly degrading its coherence, even for zero bias current. For example, borrowing the techniques developed in Ref. 26, we estimate that a 5% asymmetry in the critical current of the SQUID junctions would reduce $\tau_\phi$ from 226 $\mu$s to approximately 1 $\mu$s at the degeneracy point for case B with $I_s=0$. However, it should be possible to compensate for this asymmetry by adjusting $I_s$.\textsuperscript{27}

V. CONCLUSION

The need to resolve the state of a flux qubit in a single measurement while maintaining a weak coupling between the qubit and SQUID drives the development of techniques to enhance the sensitivity of the SQUID without a concomitant increase in the decoherence induced in the qubit. This requirement has led us to calculate the escape widths for a SQUID with an arbitrary, frequency-dependent shunt admittance across each junction, and with an arbitrary magnetic flux bias, in both the thermal and quantum regimes. We find that an appropriately designed, series $R_sC_s$ shunt suppresses the thermal-to-quantum crossover temperature $T^*$, leading to narrower escape widths at low temperatures.

We used this model to explain the temperature dependence of the escape width for a SQUID equipped with such shunts for several values of flux bias. This device showed a switching distribution at low temperature that was narrower than what one would expect from a corresponding unhunted SQUID, improving the resolution by a factor of nearly 3. However, for this model to explain the observed degree of narrowing required a shunt capacitance an order of magnitude larger than the $a priori$ value estimated for the interdigitated capacitors we constructed. We explained this result by including the effect of the SQUID lead impedance on the switching process; a model employing the $a priori$ value of shunt capacitance combined with a lead impedance close to 50 $\Omega$ gave good agreement with the experimental data.

We further calculated the decoherence induced in a flux qubit by a SQUID with arbitrary shunt admittances. As a numerical example, we modeled a system in which we measured $R_sC_s$-shunted SQUID, using the $a priori$ value of shunt capacitance and including the lead impedance, is coupled to a hypothetical (but realistic) qubit with parameters chosen to yield single-shot readout. This combination of devices yielded a dephasing time that ranged from about 200 $\mu$s at the degeneracy point to 30 $\mu$s at an energy bias of 10 GHz. These times are orders of magnitude longer than those observed in flux qubits due to inhomogeneous broadening\textsuperscript{2,6} and obtained recently by means of spin echoes.\textsuperscript{27} However, we emphasize that these calculated results are for a symmetric SQUID; when an asymmetry in the SQUID junction critical currents is included, the dephasing times are likely to be substantially reduced. This decoherence can be mitigated by including sufficiently large resistors in series with the SQUID leads.

As is made clear in Fig. 9, one can suppress $T^*$, and thereby narrow the low-temperature escape widths, by reducing the shunt resistance $R_s$, or increasing the shunt capacitance $C_s$, or by a combination of both. Furthermore, inspection of Eq. (31) shows that $J(\omega)\rightarrow 0$ as $R_s\rightarrow 0$, so that the decoherence due to the shunts vanishes in this limit. Thus, a design with a purely capacitive shunt across each junction is the natural solution to the problem of obtaining a narrow distribution.

ACKNOWLEDGMENTS

We are grateful to I. Serban for carefully checking the calculations in Sec. IV. We thank M. H. Devoret, D. Esteve,
H. Grabert, C. J. P. M. Harmans, J. M. Martinis, R. McDermott, J. E. Mooij, F. Portier, R. J. Schoelkopf, and D. Vion for helpful discussions. This work was supported by the Air Force Office of Scientific Research under Grant No. F49620-02-1-0295, the Army Research Office under Grant Nos. DAAD-19-02-1-0187 and P-43385-PH-QC, the National Science Foundation under Grant No. EIA-020-5641, the Advanced Research and Development Activity, and the Deutsche Forschungsgemeinschaft through Sonderforschungsbereich 631.

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